


Search Notes 	Application/Control No. 10686396	Applicant(s)/Patent Under Reexamination ISHIHARA, KEIICHIRO
	Examiner Jonathan R Beckley	Art Unit 4178

SEARCHED			
Class	Subclass	Date	Examiner
358	2,99,2,1,3,24,3,26	11/1/2007	JB
359	202,220,210,206,212,364,714,649,14,234,201,205,619,8 19,207,254,726,783,744	11/1/2007	JB
250	235	11/1/2007	JB
73	620	11/1/2007	JB
353	7,98,74,82	11/1/2007	JB
356	630	11/1/2007	JB
345	9	11/1/2007	JB
600	178	11/1/2007	JB
349	113	11/1/2007	JB
358	2,99,2,1,3,24,3,26	5/22/2008	JB
359	202,220,210,206,212,364,714,649,14,234,201,205,619,8 19,207,254,726,783,744	5/22/2008	JB
358	2,99,2,1,3,24,3,26	12/18/2008	JB
359	202,220,210,206,212,364,714,649,14,234,201,205,619,8 19,207,254,726,783,744	12/18/2008	JB

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	7/3/2007	JB
EAST	10/24/2007	JB
EAST	10/25/2007	JB
EAST	10/29/2007	JB
EAST	10/31/2007	JB
EAST	11/1/2007	JB
CONSULTED WITH HAI TRAN	7/3/2007	JB
CONSULTED WITH SCOTT BEALIVEAU	10/31/2007	JB
EAST	5/22/2008	JB
EAST	12/18/2008	JB
CONSULTED WITH SCOTT BEALIVEAU	12/18/2008	JB
CONSULTED WITH VICTOR KOSTAK	12/18/2008	JB
CONSULTED WITH JOSEPH MARTINEZ	12/18/2008	JB
CONSULTED WITH JESSICA STULTZ	12/18/2008	JB

/JONATHAN R BECKLEY/
Examiner,Art Unit 2625

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/JONATHAN R BECKLEY/ Examiner,Art Unit 2625	
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